IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Kazutaka Yanagita et al.

Group Art Unit: to be assigned

Serial No.: to be assigned

Examiner: to be assigned

Filed: August 13, 2003

For: SAMPLE PROCESSING SYSTEM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

This Information Disclosure Statement is filed in accordance with 37 C.F.R. §§1.56, 1.97 and 1.98. The items listed on Form PTO-1449, a copy of which is not enclosed, are made of record to assist the Patent and Trademark Office in its examination of this application. The Examiner is respectfully requested to fully consider the items and to independently ascertain their teaching.

1.

For each of the following items listed on the enclosed copy of Form PTO-1449 that is

- not in the English language, an English language translation of that item or a portion thereof or a concise explanation of the relevance of that item is enclosed:

 2. For each of the following items listed on the enclosed copy of Form PTO-1449 that is not in the English language, a concise explanation of the relevance of that item is incorporated in the specification of the above-identified application.
- 3. Any copy of the items listed on the enclosed copy of Form PTO-1449 that is not enclosed with this Information Disclosure Statement was previously cited by or submitted to the Patent and Trademark Office in application Serial No. 10/153,608, filed May 24, 2002.

PATENT Attorney's Docket No. <u>1232-4590US2</u>

4.		No fee is due under 37 C.F.R. §1.17(p) for this Information Disclosure Statement since it is being filed in compliance with:								
			37 C.F.R. §1.97(b)(1), within three months of the filing date of a national application other than a CPA; or							
			37 C.F.R. §1.97(b)(2), within three months of the date of entry into the national stage as set forth in §1.491 in an international application; or							
			37 C.F.R. §1.97(b)(3), before the mailing date of a first Office action on the merits; or							
			37 C.F.R. §1.97(b)(4) before the mailing date of a first office action after the filing of an RCE under §1.114.							
\boxtimes	for th	nis Info	sioner is hereby authorized to charge any additional fees which may be required mation Disclosure Statement, or credit any overpayment to Deposit Account, Order No. 1232-4590US2.							
			Respectfully submitted, MORGAN & FINNEGAN, L.L.P.							
Dat	ed: <u>A</u>	ugust 1	By: John A. Harroun Registration No. 46,339 (202) 857-7887 Telephone (202) 857-7929 Facsimile							
MC 345	ORGA Park	N & FI Avenue	Address: NNEGAN, L.L.P. 0154-0053							

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Attorney Docket: Serial No.: 1232-4590US2 to be assigned **FORM PTO-1449** Applicants: Examiner: Yanagita et al. to be assigned INFORMATION DISCLOSURE CITATION Filing Date: Group Art Unit: August 13, 2003 to be assigned U.S. PATENT DOCUMENTS **Publication** Examiner Sub-Initial **Patent Number** Date Name Class Class **Filing Date** AA3,493,155 02/03/70 Irving Litant et al. 2 225 12//22/70 AB3,549,446 R.W. Bennett et al. 156 230 AC 3,667,661 06/06/72 Farmer 2 225 AD 3,730,410 05/01/73 Altshuler 225 96.5 ΑE 4,962,879 10/16/90 Goesele et al. 156 281X AF 03/31/92 5,100,544 Izutani, et al. 210 75 AG 5,255,853 10/26/93 83 Munoz 177X AH 5,374,564 12/20/94 Bruel 437 24 01/03/95 ΑI 5,379,235 Fisher et al. 364 508 FOREIGN PATENT DOCUMENTS Examiner **Publication** Sub-Initial **Patent Number** Date Country Class Class Translation 0/75/98 ΑJ KR 1998-33377 Korean ☐ Yes ☐ No ΑK EP 0 709 876 A1 05/01/96 Europe ☐ Yes ☐ No ALEP 0 840 381 A2 05/06/98 Europe Yes □ No EP 0 843 345 A2 AM 5/20/98 Europe ☐ Yes ☐ No OTHER DOCUMENTS (Including Author, Title, Date, etc.) "Single-Crystal Silicon on Non-Single-Crystal Insulators", G.W. Cullen, Journal of Crystal Growth, Vol. 63, AN No. 3, pp. 429-590, 1983 "Crystalline Quality of Silicon Layer Formed by FIPOS Technology", Kazuo IMAI et al., Journal of Crystal AO Growth, Vol. 63, pp 547-553, 1987 "Silicon-On-Insulator by Wafer Bonding: A Review", W.P. Maszara, Journal of Electrochemical Society, Vol. AP 138, pp. 341-347, 1991 Examiner Date Considered

Initial if reference considered, whether or not citation is in conformance with MPEP §609.

Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

EXAMINER:

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			U.S.	PATE	NT DOCUMENTS				
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	AQ	5,510,019	4/23/96	Ya	bumoto et al.		210	137	
	AR	5,747,387	05/05/98	Ko	izumi et al.		438	906X	
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-	BA	EP 1 026 729 A2	08/09/00	Eu	rope				⊠ Yes □ No
	BB	EP 1 045 448 A1	10/18/00	Eu	rope				☐ Yes ☐ No
	ВС	EP 0 926 719 A2	06/30/99	Eu	irope				☐ Yes ☐ No
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	FOR	M PTO-1449		1232-4590US2 to be assigned Applicants Examiner:					
				Yanagita et al. to		to be assigned			
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Examiner Initial		Patent Number	Publication Date	on	Name	Class	Sub- Class	Filing Date	
	BG	6,221,740	4/24/01	В	Bryan et al.	438	458		
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	BP	5-21338	1/29/93	Ј	apan			English Abstract	
	BQ	7-302889	11/14/95	Ј	apan			English Abstract	
	BR	WO 99/06110	02/11/99	V	VO .			☐ Yes ☐ No	
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	BW "A New Dielectric Isolation Method Using Porous Silicon", K. Imai, Solid – State Electronics, Vol. 224, pp. 159-164, 1981								
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INFORMATION DISCLOSURE CITATION

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Attorney Docket:	Serial No.:	
1232-4590US2	to be assigned	
Applicants	Examiner:	
Yanagita et al.	to be assigned	
Filing Date:	Group Art Unit:	· · · · · · · · · · · · · · · · · · ·
August 13, 2003	to be assigned	

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	BY	4,208,760	6/24/80	Dexter et al.	15	302	12/19/77
	BZ	4,215,928	8/5/80	Bayley et al.	354	319	3/30/79
	CA	4,850,381	7/25/89	Moe et al.	134	62	2/1/88
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	CC	5,357,645	10/25/94	Onodera	15	97.1	5/14/93
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	СН	JPA60-05530	1/14/94	Japan			English Abstract
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CJ	"Silicon on Insulator Material by Wafer Bonding", Christine Harendt, Charles E. Hunt e al., <i>Journal of Electronic Materials</i> , vol. 20, pp. 267-277, 1991
CK	Michel Bruel, et al. "Smart-Cut: A New Silicon On Insulator Material Technology Based On Hydrogen Implantation And Wafer Bonding", Jpn. J. Appl. Phys. Vol. 36, No. 3B, Part 01, March 1, 1997, pages 1636-1641.
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	CX	ЈРА63-16455	11/15/94		Japan			English Abstract	
	CY	JPA9-167724	6/24/97		Japan			English Abstract	
	CZ							☐ Yes ☐ No	
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	DA	U.S. Application S Method."	Serial No. 09	/434,	740, filed November 11, 2	002, entitled "Sample	e Separating	Apparatus and	
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